

08/31/01

ISSUE CLASSIFICATION	
Class	Subject

U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

SCANNED 314 Q.A. UH

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/943696		356	B65C	2877	WILLIAMS

APPLICANTS

Henry Simon
Robert Deck
Richard Andaloro

TITLE

Method of measuring surface plasmon resonance using interference structure of reflected beam profile

ISSUING CLASSIFICATION

TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____				ISSUE FEE	
				Amount Due	Date Paid
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed				ISSUE BATCH NUMBER	

WARNING:

WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.